

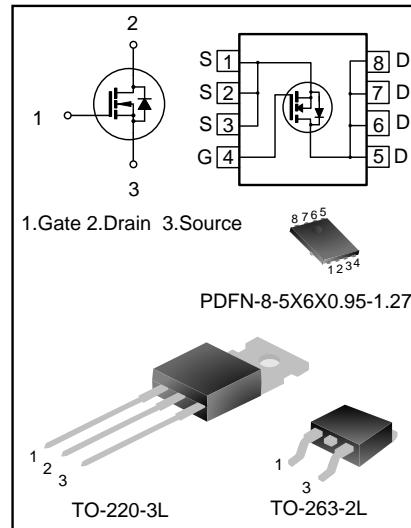


## 120A, 85V N-CHANNEL MOSFET

### DESCRIPTION

The SVT085R5NT/S/L5 is an N-channel enhancement mode power MOS field effect transistor which is produced using Silan's LVMOS technology. The improved process and cell structure have been especially tailored to minimize on-state resistance, provide superior switching performance.

This device is widely used in the fields of uninterruptible power supplies and power management of inverter systems.



### FEATURES

- 120A, 85V,  $R_{DS(on)(typ.)}=4.5m\Omega @ V_{GS}=10V$
- Low gate charge
- Low Crss
- Fast switching
- Improved dv/dt capability

### ORDERING INFORMATION

Part No.	Package	Marking	Hazardous Substance Control	Packing Type
SVT085R5NT	TO-220-3L	085R5NT	Pb free	Tube
SVT085R5NS	TO-263-2L	085R5NS	Halogen free	Tube
SVT085R5NSTR	TO-263-2L	085R5NS	Halogen free	Tape&Reel
SVT085R5NL5TR	PDFN-8-5X6X0.95-1.27	085R5NL5	Halogen free	Tape&Reel

### ABSOLUTE MAXIMUM RATINGS (UNLESS OTHERWISE NOTED, $T_c=25^\circ C$ )

Characteristics	Symbol	Ratings		Unit
		SVT085R5NT/S	SVT085R5NL5	
Drain-Source Voltage	$V_{DS}$	85		V
Gate-Source Voltage	$V_{GS}$	$\pm 20$		V
Drain Current	$I_D$	120	100	A
		90	64	
Drain Current Pulsed	$I_{DM}$	480	400	A
Power Dissipation ( $T_c=25^\circ C$ ) -Derate above $25^\circ C$	$P_D$	160	114	W
		1.3	0.9	W/ $^\circ C$
Single Pulsed Avalanche Energy (Note 1)	$E_{AS}$	324		mJ
Operation Junction Temperature Range	$T_J$	-55~+150		$^\circ C$
Storage Temperature Range	$T_{stg}$	-55~+150		$^\circ C$



## THERMAL CHARACTERISTICS

Characteristics	Symbol	Ratings		Unit
		SVT085R5NT/S	SVT085R5NL5	
Thermal Resistance, Junction-to-Case	R <sub>θJC</sub>	0.78	1.1	°C/W
Thermal Resistance, Junction-to-Ambient	R <sub>θJA</sub>	62.5	50	°C/W

## ELECTRICAL CHARACTERISTICS (UNLESS OTHERWISE NOTED, T<sub>C</sub>=25°C)

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	85	--	--	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =85V, V <sub>GS</sub> =0V	--	--	1.0	μA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	--	--	±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250μA	2.0	--	4.0	V
Static Drain- Source On State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =50A	--	4.5	5.5	mΩ
Gate Resistance	R <sub>G</sub>	f=1MHz	--	1.9	--	Ω
Input Capacitance	C <sub>iss</sub>	f=1MHz, V <sub>GS</sub> =0V, V <sub>DS</sub> =40V	--	4281	--	pF
Output Capacitance	C <sub>oss</sub>		--	669	--	
Reverse Transfer Capacitance	C <sub>rss</sub>		--	17	--	
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> =40V, V <sub>GS</sub> =10V, R <sub>G</sub> =24Ω, I <sub>D</sub> =13.3A (Notes 2,3)	--	41	--	ns
Turn-on Rise Time	t <sub>r</sub>		--	68	--	
Turn-off Delay Time	t <sub>d(off)</sub>		--	164	--	
Turn-off Fall Time	t <sub>f</sub>		--	85	--	
Total Gate Charge	Q <sub>g</sub>	V <sub>DD</sub> =40V, V <sub>GS</sub> =10V, I <sub>D</sub> =50A (Notes 2,3)	--	68	--	nC
Gate-Source Charge	Q <sub>gs</sub>		--	28	--	
Gate-Drain Charge	Q <sub>gd</sub>		--	17	--	

## SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	I <sub>s</sub>	Integral Reverse P-N Junction Diode in the MOSFET	--	--	120	A
Pulsed Source Current	I <sub>SM</sub>		--	--	480	
Diode Forward Voltage	V <sub>SD</sub>	I <sub>s</sub> =50A, V <sub>GS</sub> =0V	--	--	1.3	V
Reverse Recovery Time	T <sub>rr</sub>	I <sub>s</sub> =20A, V <sub>GS</sub> =0V, dI/dt=100A/μs (Notes 2)	--	59	--	ns
Reverse Recovery Charge	Q <sub>rr</sub>		--	0.12	--	

Notes:

1.L=0.5mH, I<sub>AS</sub>=36A, V<sub>DD</sub>=64V, R<sub>G</sub>=10Ω, starting T<sub>J</sub>=25°C;

2.Pulse Test: Pulse width ≤300μs, Duty cycle≤2%;

3.Essentially independent of operating temperature.



## TYPICAL CHARACTERISTICS

Figure 1. Output Characteristics

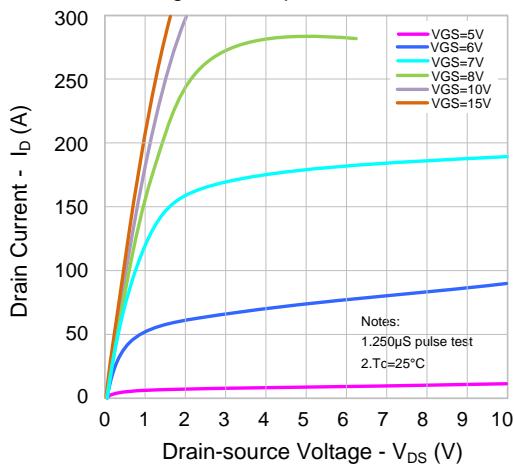


Figure 2. Transfer Characteristics

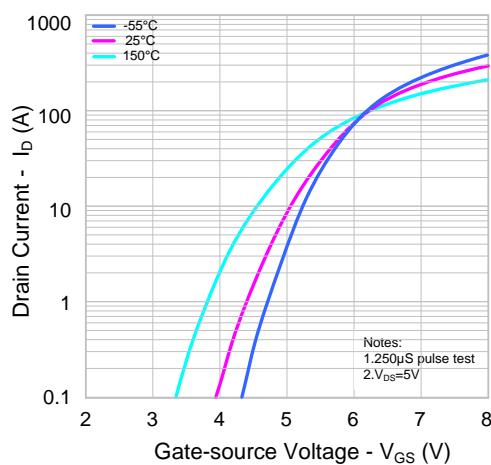


Figure 3. On-resistance vs. Drain Current

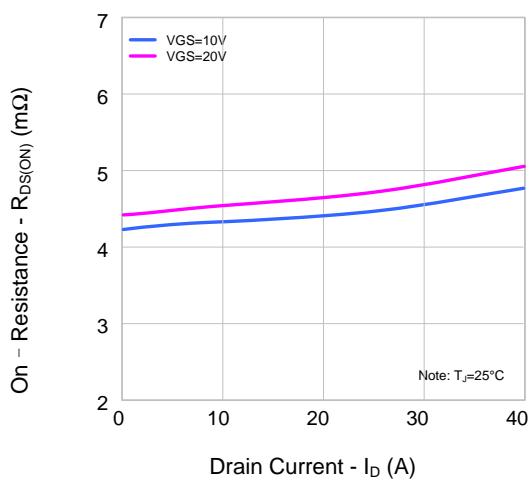


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

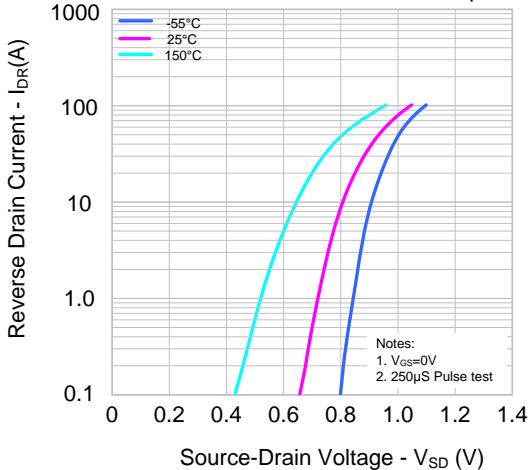


Figure 5. Capacitance Characteristics

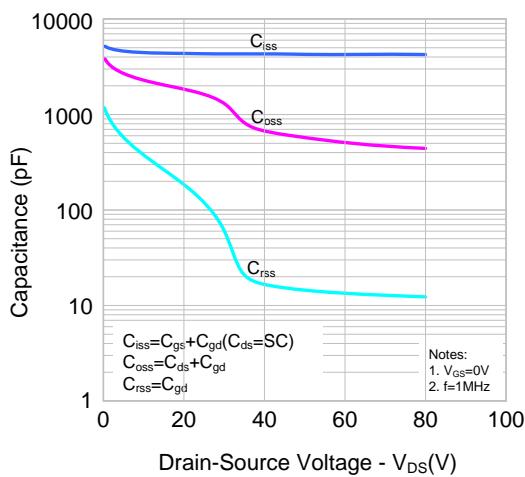
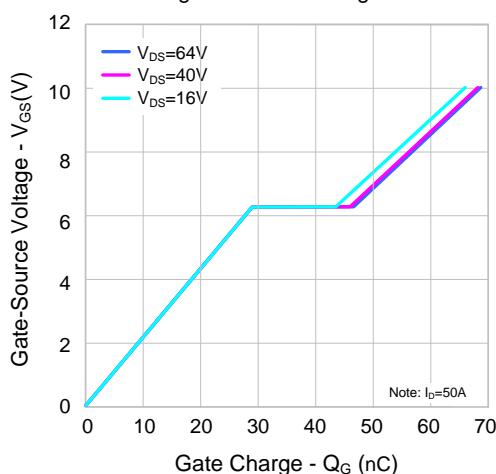


Figure 6. Gate Charge





## TYPICAL CHARACTERISTICS (CONTINUED)

Figure 7. Breakdown Voltage vs.  
Temperature Characteristics

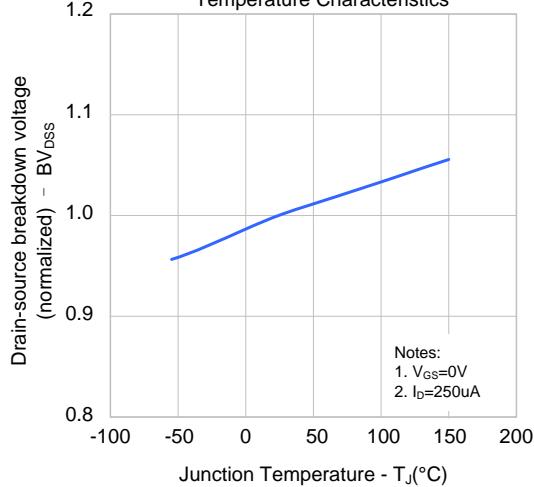


Figure 8. On-resistance vs. Temperature  
Characteristics

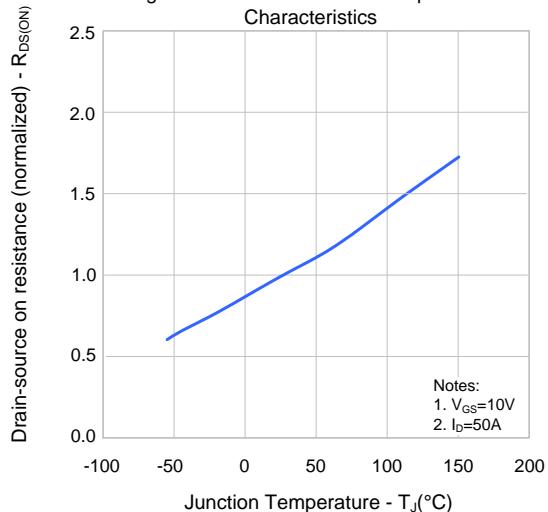


Figure 9-1. Max. Safe Operating Area  
(SVT085R5NT/S)

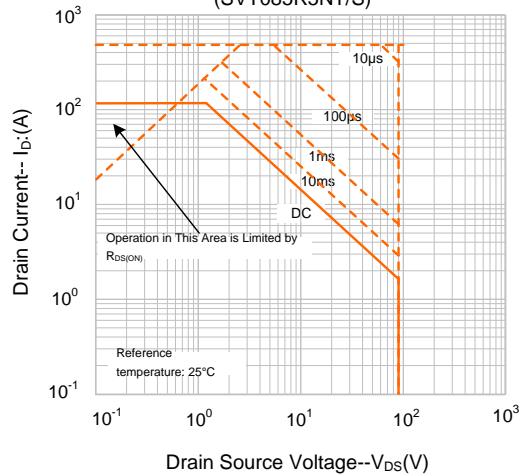
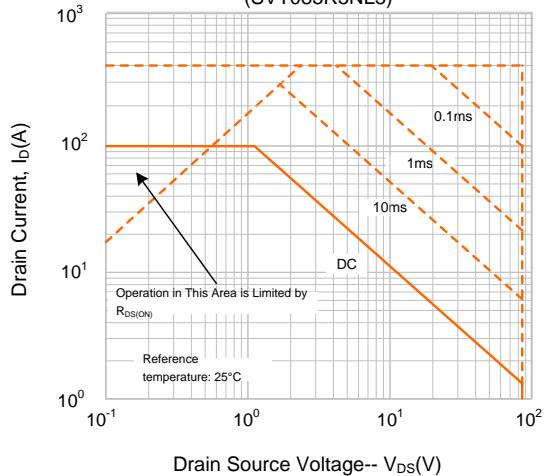
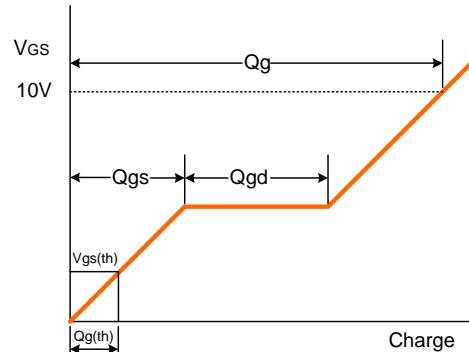
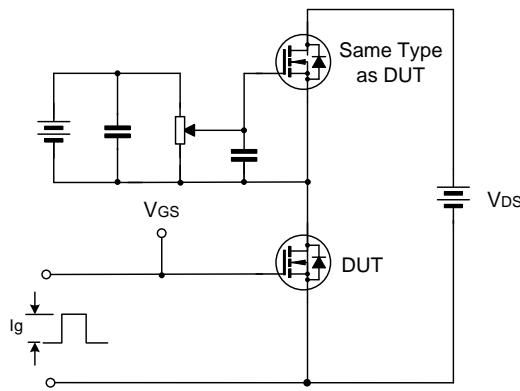


Figure 9-2. Max. Safe Operating Area  
(SVT085R5NL5)

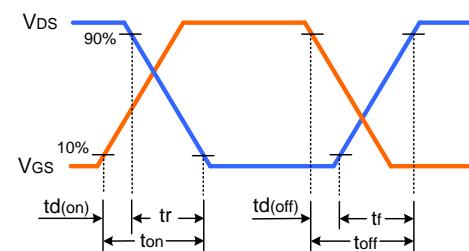
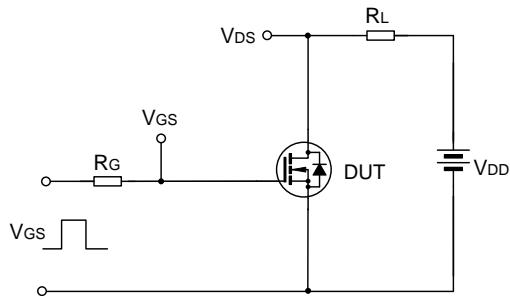




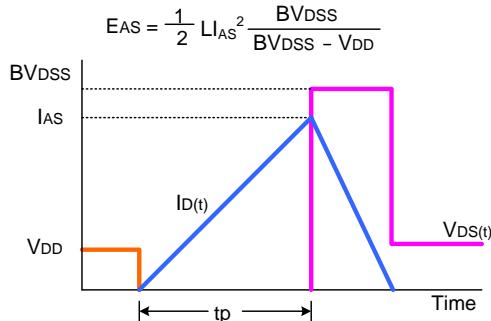
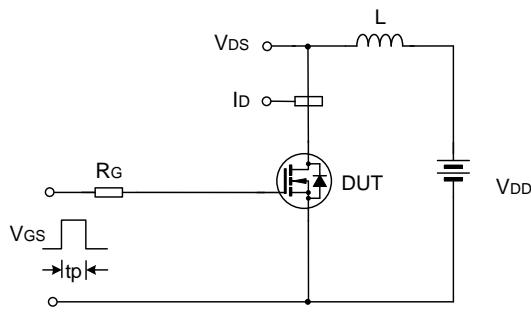
## TYPICAL TEST CIRCUIT



Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveform



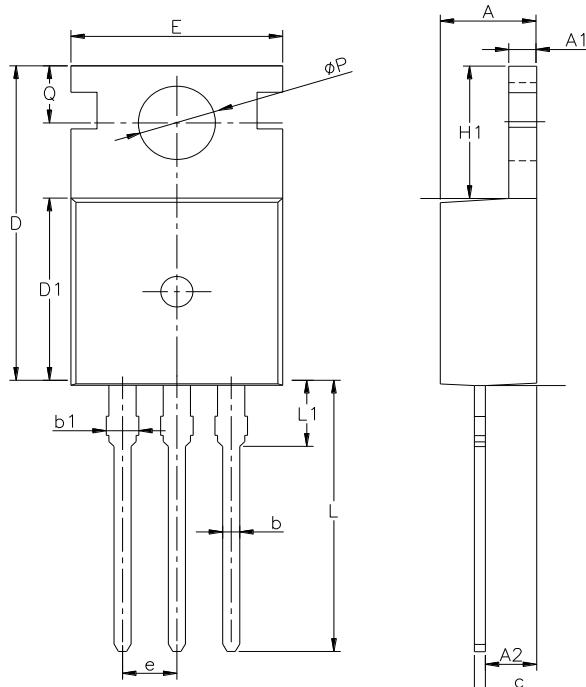
Unclamped Inductive Switching Test Circuit & Waveform



PACKAGE OUTLINE

TO-220-3L

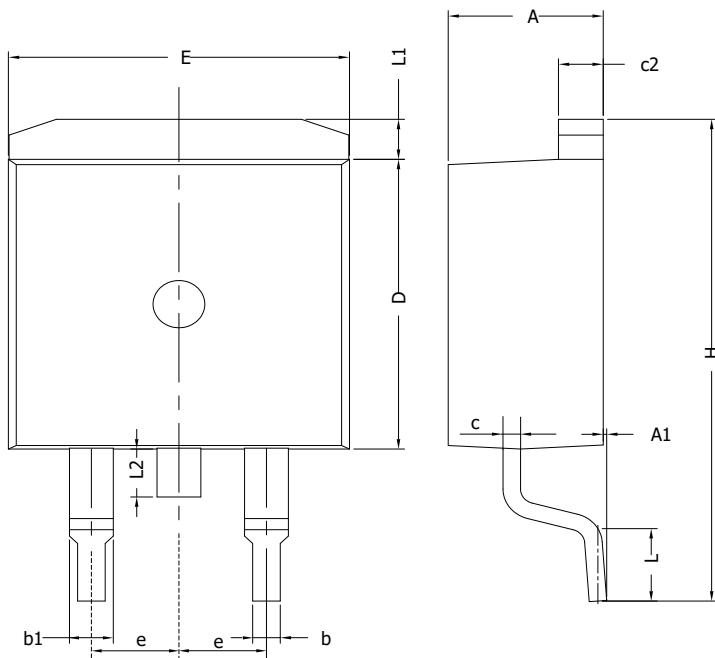
UNIT: mm



SYMBOL	MIN	NOM	MAX
A	4.30	4.50	4.70
A1	1.00	1.30	1.50
A2	1.80	2.40	2.80
b	0.60	0.80	1.00
b1	1.00	—	1.60
c	0.30	—	0.70
D	15.10	15.70	16.10
D1	8.10	9.20	10.00
E	9.60	9.90	10.40
e	2.54BSC		
H1	6.10	6.50	7.00
L	12.60	13.08	13.60
L1	—	—	3.95
φP	3.40	3.70	3.90
Q	2.60	—	3.20

TO-263-2L

UNIT: mm



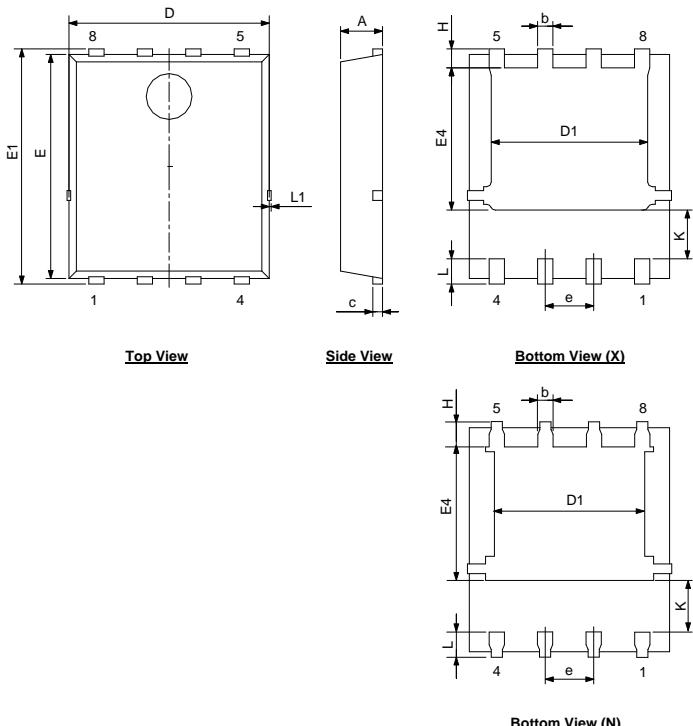
SYMBOL	MIN	NOM	MAX
A	4.30	4.57	4.72
A1	0	0.10	0.25
b	0.71	0.81	0.91
c	0.30	---	0.60
c2	1.17	1.27	1.37
D	8.50	---	9.35
E	9.80	---	10.45
e	2.54BSC		
H	14.70	---	15.75
L	2.00	2.30	2.74
L1	1.12	1.27	1.42
L2	---	---	1.75



## PACKAGE OUTLINE(CONTINUED)

PDFN-8-5X6X0.95-1.27

UNIT: mm



SYMBOL	X			N		
	MIN	NOM	MAX	MIN	NOM	MAX
A	0.90	1.10	1.30	0.90	0.95	1.00
c	0.154	0.254	0.354	0.21	0.25	0.34
D	4.90	5.20	5.50	4.80	4.90	5.00
E	5.56	5.86	6.16	5.70	5.75	5.80
D1	3.80	4.10	4.30	3.91	4.01	4.11
E1	5.85	6.15	6.45	5.90	6.00	6.10
b	0.20	0.40	0.60	0.35	0.45	0.55
K	1.10	1.30	1.50	1.10	--	--
e	1.07	1.27	1.37	1.17	1.27	1.37
E4	3.52	3.72	3.92	3.34	3.44	3.54
L	0.36	0.66	0.76	0.51	0.61	0.71
L1	--	--	0.12	--	--	0.10
H	0.30	0.50	0.70	0.51	0.61	0.71

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Rev.: 1.7

Revision History:

1. Update Electrical schematic and typical test circuit
- 

Rev.: 1.6

Revision History:

1. Modify Electrical characteristics and curves
- 

Rev.: 1.5

Revision History:

1. Modify Electrical characteristics
- 

Rev.: 1.4

Revision History:

1. Add the package outline of PDFN-8-5X6X0.95-1.27
- 

Rev.: 1.3

Revision History:

1. Update the Electrical characteristics
  2. Update Fig 5 and 6
- 

Rev.: 1.2

Revision History:

1. Update the package outline of TO-220-3L
- 

Rev.: 1.1

Revision History:

1. Add TO-263-2L
- 

Rev.: 1.0

Revision History:

1. First release
-